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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): Douglas D. Coolbaugh, et al.

Examiner:

Unassigned

Serial No:

10/711144

Art Unit:

Unassigned

Filed:

8/27/04

Docket:BUR920040107US1 (17619)

For: MOS VARACTOR USING ISOLATION WELL Dated:

August 6, 2004

Commissioner for Patents Alexandria, VA 23313-1450

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Sir:

In accordance with 37 C.F.R. §§ 1.97 and 1.98, it is requested that the following references, which are also listed on the attached Form PTO-1449, be made of record in the above-identified case.

- 1. European Patent Publication No. EP0902483 A1, published on March 17, 1999;
- 2. International Patent Publication No. WO 03/043079A1, published on May 22, 2003;
- 3. Joachim N. Burghartz, et al., "Integrated RF and Microwave Components in BiCMOS Technology", IEEE Transactions On Electron Devices, Vol. 43, No. 9, September 1996 (pp. 1559-1570); and
- 4. R.A. Moline, et al., "Ion-Implanted Hyperabrupt Junction Voltage Variable Capacitors", IEEE Transactions On Electron Devices, Vol. ED-19, No. 2, February 1972 (pp. 267-273).

CERTIFICATE OF MAILING UNDER 37 C.F.R. §1.8(a)

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, Box 1450, Alexandria, VA 22313-1450 on

Dated: 2/3//04

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Applicants are submitting copies of the above-cited references.

Inasmuch as this Information Disclosure Statement is being submitted in accordance with the schedule set out in 37 C.F.R. § 1.97(b), no statement or fee is required.

Respectfully submitted,

Leslie S. Szivos, Ph.D.

Registration No.: 39,394

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LSS/sf Enclosure

PTO Form 1449

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE (REV. 7-80)PATENT AND TRADEMARK OFFICE				Atty. Docket No. BUR920040107US1 (17619)			Serial No. 10/711144			
Use several sheets if necessary)					Applicant Douglas D. Coolbaugh, et al.					
					ng Date 8/27/04	Group Unassigned				
U.S. PATENT DOCUMENTS										
EXAMINER INITIAL*		DOCUMENT NUMBER	DATE	NAME		CLASS	SUBCLASS	SUBCLASS FILING DATE (if appropriate)		
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FOREIGN PATENT DOCUMENTS										
		DOCUMENT NUMBER	DATE	COUNTRY		CLASS	SUBCLASS	TRANSLATION		
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		EP0902483 A1	3/17/1999		EPO					
		WO 03/043079 A1	5/22/2003		PCT					
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OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)										
		Joachim N. Burghartz, et al., "Integrated RF and Microwave Components in BiCMOS Technology", IEEE Transactions On Electron Devices, Vol. 43, No. 9, September 1996 (pp. 1559-1570); and								
		R.A. Moline, et al., "Ion-Implanted Hyperabrupt Junction Voltage Variable Capacitors", IEEE Transactions On Electron Devices, Vol. ED-19, No. 2, February 1972 (pp. 267-273).								
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EXAMINER				DA	DATE CONSIDERED					
* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.										